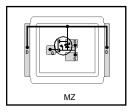


# IRF6643TRPbF

#### **Features**

- Latest MOSFET silicon technology
- Key parameters optimized for Class-D audio amplifier applications
- Low R<sub>DS(on)</sub> for improved efficiency
- Low Qg for better THD and improved efficiency
- · Low Qrr for better THD and lower EMI
- Low package stray inductance for reduced ringing and lower FMI
- Can deliver up to 200 W per channel into  $8\Omega$  load in half-bridge configuration amplifier
- Dual sided cooling compatible
- · Compatible with existing surface mount technologies
- · RoHS compliant, halogen-free
- Lead-free (qualified up to 260°C reflow)

Key Parameters						
V <sub>DS</sub>	150	V				
$R_{DS(ON)}$ typ. @ $V_{GS}$ = 10V	29	mΩ				
Qg typ.	39	nC				
R <sub>G(int)</sub> typ.	0.9	Ω				





May 31, 2013

Applicable DirectFET Outline and Substrate Outline (see p.6, 7 for details)

SH	SJ	ST	SH	MQ	MX	MT	MN	MZ	

#### **Description**

This Digital Audio MOSFET is specifically designed for Class-D audio amplifier applications. This MOSFET utilizes the latest processing techniques to achieve low on-resistance per silicon area. Furthermore, gate charge, body-diode reverse recovery and internal gate resistance are optimized to improve key Class-D audio amplifier performance factors such as efficiency, THD, and EMI.

The IRF6643PbF device utilizes DirectFET® packaging technology. DirectFET® packaging technology offers lower parasitic inductance and resistance when compared to conventional wirebonded SOIC packaging. Lower inductance improves EMI performance by reducing the voltage ringing that accompanies fast current transients. The DirectFET® package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when application note AN-1035 is followed regarding the manufacturing method and processes. The DirectFET® package also allows dual sided cooling to maximize thermal transfer in power systems, improving thermal resistance and power dissipation. These features combine to make this MOSFET a highly efficient, robust and reliable device for Class-D audio amplifier applications.

Base part number	Package Type	Standard P	ack	Orderable Part Number
		Form	Quantity	
IRF6643TRPbF	DirectFET Medium Can	Tape and Reel	4800	IRF6643TRPbF

#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
$V_{GS}$	Gate-to-Source Voltage	±20	V
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	35	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	6.2	
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	5.0	Α
I <sub>DM</sub>	Pulsed Drain Current ①	76	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	89	
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation ③	2.8	W
P <sub>D</sub> @T <sub>A</sub> = 70°C	Power Dissipation ③	1.8	
E <sub>AS</sub>	Single Pulse Avalanche Energy ②	50	mJ
I <sub>AR</sub>	Avalanche Current ①	7.6	А
	Linear Derating Factor	0.022	W/°C
TJ	Operating Junction and	-40 to + 150	°C
$T_{STG}$	Storage Temperature Range		

Notes ① through ⑨ are on page 9



## **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient ③		45	
$R_{ heta JA}$	Junction-to-Ambient ©	12.5		
$R_{ heta JA}$	Junction-to-Ambient ⑦	20		°C/W
$R_{ heta JC}$	Junction-to-Case ® 9		1.4	
$R_{\theta J\text{-PCB}}$	Junction-to-PCB Mounted	1.0		

## Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	150			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.18		V/°C	Reference to 25 $^{\circ}$ C, I <sub>D</sub> = 1.0mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		29	34.5	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 7.6A ④
$V_{GS(th)}$	Gate Threshold Voltage	3.0	4.0	4.9	V	$V_{DS} = V_{GS}$ , $I_D = 150\mu A$
$\Delta V_{GS(th)}$	Gate Threshold Voltage Coefficient		-11		mV/°C	
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20	μA	$V_{DS} = 150V, V_{GS} = 0V$
				250		$V_{DS} = 120V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
$I_{GSS}$	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$
$R_G$	Gate Resistance		0.8		Ω	

# Dynamic @ T<sub>J</sub> = 25°C (unless otherwise specified)

gfs	Forward Transconductance	16			S	$V_{DS} = 10V, I_{D} = 7.6A$
$Q_g$	Total Gate Charge		39	55		
Q <sub>gs1</sub>	Pre-VthGate-to-Source Charge		9.6			$V_{DS} = 75V$
Q <sub>gs2</sub>	Post-Vth Gate-to-Source Charge		2.2			V <sub>GS</sub> = 10V
$Q_{gd}$	Gate-to-Drain Charge		11	17	nC	$I_{D} = 7.6A$
Q <sub>godr</sub>	Gate Charge Overdrive		16			
Q <sub>sw</sub>	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )		13			
$t_{d(on)}$	Turn-On Delay Time		9.2			
t <sub>r</sub>	Rise Time		5.0		ns	$V_{DD} = 75V, V_{GS} = 10V$
$t_{d(off)}$	Turn-Off Delay Time		13			$I_{D} = 7.6A$
t <sub>f</sub>	Fall Time		4.4			
C <sub>iss</sub>	Input Capacitance		2340			V <sub>GS</sub> = 0V
Coss	Output Capacitance		300			$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		61		рF	f = 1.0MHz
Coss	Output Capacitance		1950			V <sub>GS</sub> =0V, V <sub>DS</sub> =1.0V, <i>f</i> =1.0MHz
Coss	Output Capacitance		140			V <sub>GS</sub> =0V, V <sub>DS</sub> =80V, <i>f</i> =1.0MHz

## **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			58		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			76	A	integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 7.6A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		67	100	ns	$T_J = 25^{\circ}C$ , $I_F = 7.6A$ , $V_{DD} = 50V$
$Q_{rr}$	Reverse Recovery Charge		190	280	nC	di/dt = 100A/µs ④

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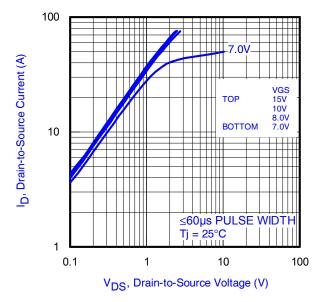


Fig 1. Typical Output Characteristics

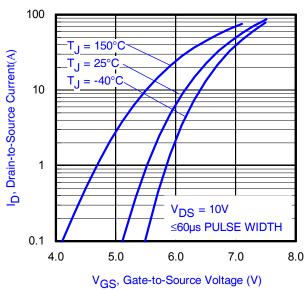


Fig 3. Typical Transfer Characteristics

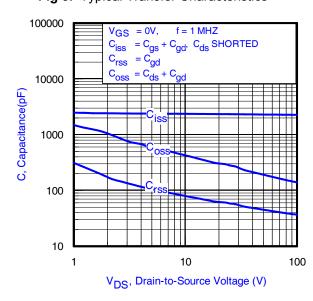


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

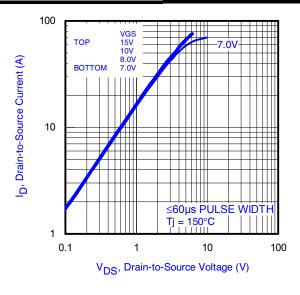


Fig 2. Typical Output Characteristics

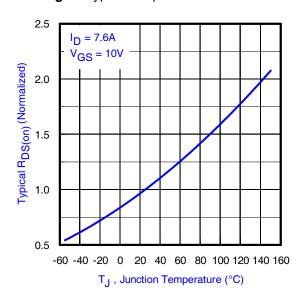


Fig 4. Normalized On-Resistance vs. Temperature

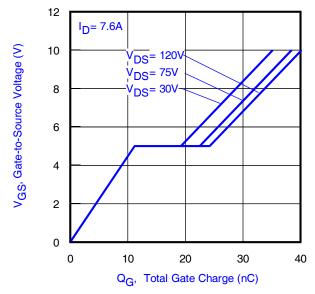


Fig 6. Typical Gate Charge vs Gate-to-Source Voltage



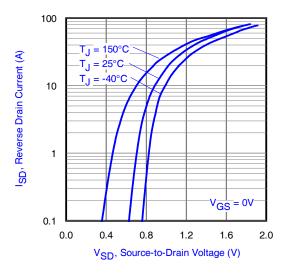


Fig 7. Typical Source-Drain Diode Forward Voltage

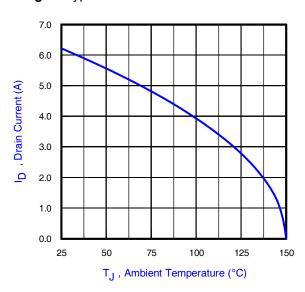


Fig 9. Maximum Drain Current vs. Ambient Temperature

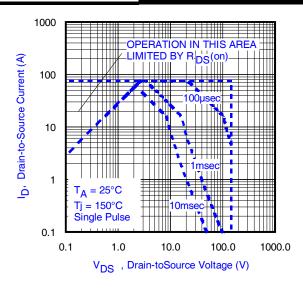
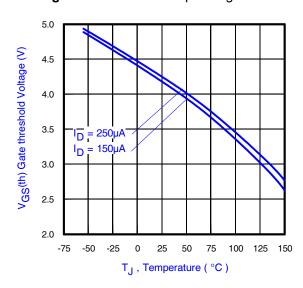


Fig 8. Maximum Safe Operating Area



**Fig 10.** Typical Threshold Voltage vs. Junction Temperature

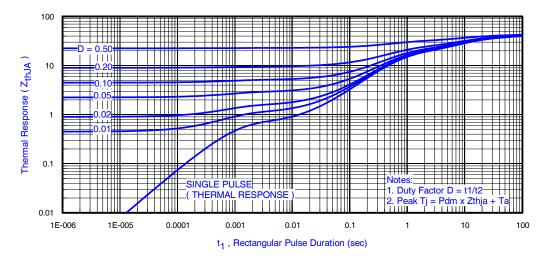


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient ③

4



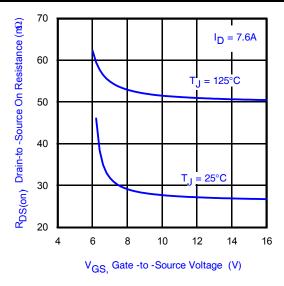


Fig 12. Typical On-Resistance vs. Gate Voltage

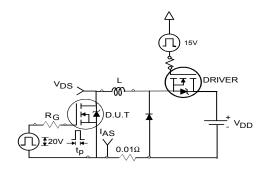


Fig 15a. Unclamped Inductive Test Circuit

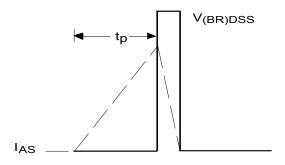


Fig 15b. Unclamped Inductive Waveforms

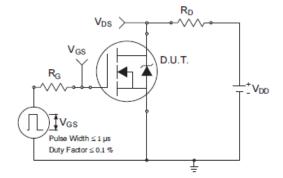


Fig 16a. Switching Time Test Circuit

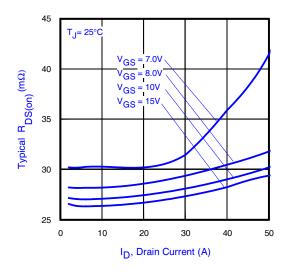


Fig 13. Typical On-Resistance vs. Drain Current

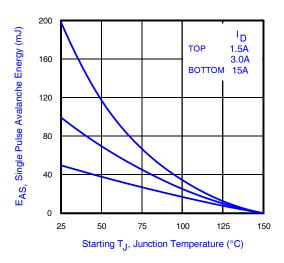


Fig 14. Maximum Avalanche Energy vs. Drain Current

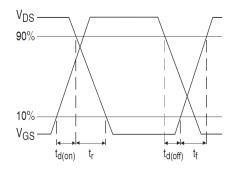


Fig 16b. Switching Time Waveforms



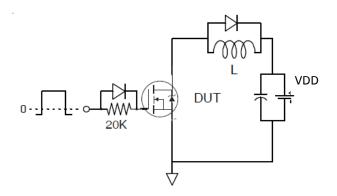


Fig 17a. Gate Charge Test Circuit

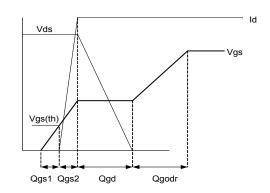


Fig 17b. Gate Charge Waveform

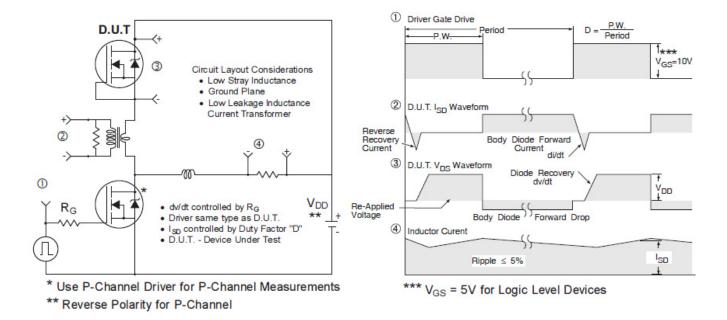
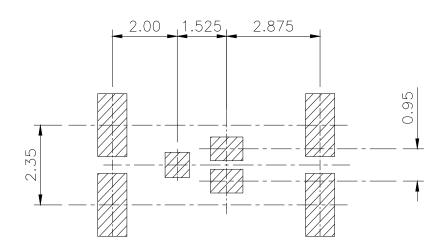


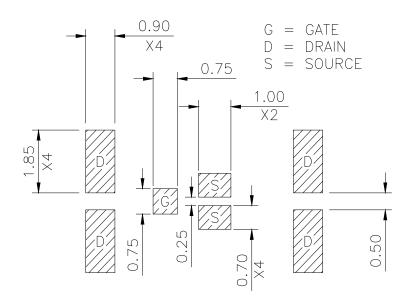
Fig 18. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



# DirectFET® Substrate and PCB Layout, MZ Outline (Medium Size Can, Z-Designation).

Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET. This includes all recommendations for stencil and substrate designs.





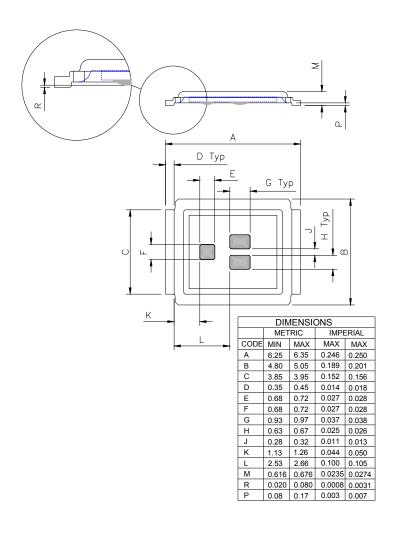
Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

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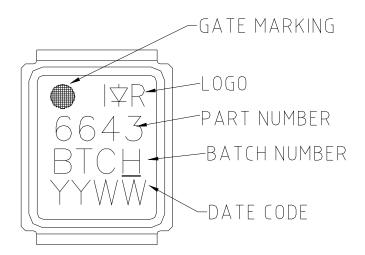


## **DirectFET® Outline Dimension, MZ Outline** (Medium Size Can, D-Designation).

Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET. This includes all recommendations for stencil and substrate designs.



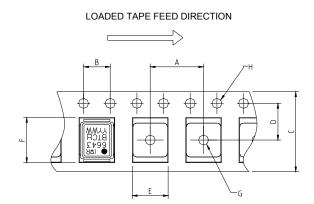
## **DirectFET® Part Marking**



Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

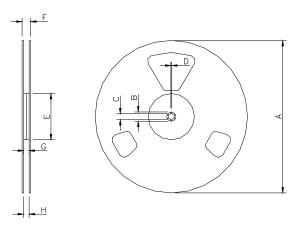


# DirectFET® Tape & Reel Dimension (Showing component orientation).



NOTE: CONTROLLING DIMENSIONS IN MM

DIMENSIONS							
	ME	TRIC	IMP	ERIAL			
CODE	MIN	MAX	MIN	MAX			
Α	7.90	8.10	0.311	0.319			
В	3.90	4.10	0.154	0.161			
С	11.90	12.30	0.469	0.484			
D	5.45	5.55	0.215	0.219			
E	5.10	5.30	0.201	0.209			
F	6.50	6.70	0.256	0.264			
G	1.50	N.C	0.059	N.C			
Н	1.50	1.60	0.059	0.063			



NOTE: Controlling dimensions in mm Std reel quantity is 4800 parts. (ordered as IRF6643TRPBF). For 1000 parts on 7" reel, order IRF6643TR1PBF

	REEL DIMENSIONS								
S	TANDARI	OPTION	I (QTY 48	00)	TR	1 OPTION	(QTY 10	00)	
	ME	TRIC	IMP	ERIAL	ME	TRIC	IMP	ERIAL	
CODE	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
Α	330.0	N.C	12.992	N.C	177.77	N.C	6.9	N.C	
В	20.2	N.C	0.795	N.C	19.06	N.C	0.75	N.C	
С	12.8	13.2	0.504	0.520	13.5	12.8	0.53	0.50	
D	1.5	N.C	0.059	N.C	1.5	N.C	0.059	N.C	
Е	100.0	N.C	3.937	N.C	58.72	N.C	2.31	N.C	
F	N.C	18.4	N.C	0.724	N.C	13.50	N.C	0.53	
G	12.4	14.4	0.488	0.567	11.9	12.01	0.47	N.C	
Н	11.9	15.4	0.469	0.606	11.9	12.01	0.47	N.C	

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

## Qualification Information<sup>†</sup>

Moisture Sensitivity Level	DirectFET	MSL1 (per JEDEC J-STD-020D <sup>††)</sup>		
RoHS Compliant	Yes			

- † Qualification standards can be found at International Rectifier's web site http://www.irf.com/product-info/reliability/
- †† Applicable version of JEDEC standard at the time of product release.

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25$ °C, L = 0.43mH,  $R_G = 25\Omega$ ,  $I_{AS} = 7.6$ A.
- ③ Surface mounted on 1 in. square Cu board.
- ④ Pulse width  $\leq$  400µs; duty cycle  $\leq$  2%.
- $^{\circ}$  Coss eff. is a fixed capacitance that gives the same charging time as Coss while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- © Used double sided cooling, mounting pad with large heatsink.
- Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- ® T<sub>C</sub> measured with thermal couple mounted to top (Drain) of part.
- $\mathfrak{G}$  R<sub>θ</sub> is measured at T<sub>J</sub> of approximately 90°C.

## **Revision History**

Date	Comments					
05/30/2013	Converted the data sheet to Class-D Audio formatting template. No change in electrical parameters.					



IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA

To contact International Rectifier, please visit http://www.irf.com/whoto-call/

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